Group Testing with Prior Statistics

Tongxin Li, Chun Lam Chan, Wenhao Huang, Tarik Kaced, and Sidharth Jaggi

The Chinese University of Hong Kong

arXiv:1401.3667v7 [cs.IT] 30 Sep 2014

Abstract

We consider a new group testing model wherein each item is a binary random variable defined by an *a priori* probability of being *defective*. We assume that each probability is small and that items are independent, but not necessarily identically distributed. The goal of *group testing* algorithms is to identify with high probability the subset of defectives via non-linear (disjunctive) binary measurements. Our main contributions are two classes of algorithms: (1) adaptive algorithms with tests based either on a maximum entropy principle, or on a Shannon-Fano/Huffman code; (2) non-adaptive algorithms. Under loose assumptions and with high probability, our algorithms only need a number of measurements that is close to the information-theoretic lower bound, up to an explicitly-calculated universal constant factor. We provide simulations to support our results.

I. Introduction

The group testing model was first suggested by Dorfman [6] over sixty years ago, and has since spawned a vast affiliated literature on theory and applications (see the book [7] for a survey). The classical version of the group testing problem is that of *Combinatorial Group Testing*. In that version, it is known that there are D defective items in a population of size N (the usual assumption is that $D = o(N)$). Non-linear binary disjunctive group tests are allowed (OR), for which a subset of items is tested, and the test outcome is 1 if at least one item being tested is defective, and 0 otherwise. In that setting, if we allow an average error probability of at most P_e, the information theoretic lower bound $(1-P_e)\log_2\binom{N}{D} = (1-P_e)D\log_2\left(\frac{N}{D}\right) + \mathcal{O}(D)$ tests is necessary for both adaptive and non-adaptive algorithms (see for instance [3, 8, 13]). Adaptive group testing schemes essentially meeting this bound are known [10]; non-adaptive algorithms that meet this bound up to small multiplicative factors are also known [3]. Some results from Combinatorial Group Testing also readily carry over to the model in this paper, (called *Probabilistic Group Testing*) wherein each of the N items are i.i.d. with a small probability of being defective [18, 19].

We focus on the model where the statistics on the likelihood of any given item to be defective are available prior to the design of the testing procedure. The motivation comes from real-world examples. For instance, when testing a large population for a given disease (Dorfman's original motivation in [6]), historical data on the prevalence of the disease in specific sub-populations parametrized by age, gender,

weight, etc are often available. Specifically, in a population of size N, we denote the status of whether the ith item is defective or not by whether a corresponding binary variable X_i is 1 or 0. The length-N binary vector $\mathbf{X} \in \{0,1\}^N$ is the *population vector*, whose recovery is the objective of the group testing algorithm.

Our working hypothesis on prior statistics is that items might have different *a priori* probabilities of being defective and are independent[1]. The knowledge of prior statistics can reduce significantly the number of required tests in some scenarios. Consider the following – given the probability vector $(p_1, \ldots, p_N)$ one can compute the *expected number of defective items* as μ, defined as the sum $\sum_i^N p_i$ of the individual probabilities, and in fact by standard statistical arguments [11] this quantity can even be "concentrated" (for large enough N it can be shown that with high probability the actual number of defective items is "relatively close" to its expectation). One might then naïvely try to use existing Probabilistic Group Testing algorithms, under the assumption that an upper bound for D, the number of defectives, is given by $(1+\delta)\mu$, for some "small" δ. An immediate issue of most Probabilistic Group Testing algorithms is they assume that the prior statistics are, in one form or another, uniform – each item is equally likely to be defective. It is therefore by no means clear why those algorithms would have the same performance in our scenario (a naïve translation of results would indicate high probability of recovery with $c\mu\log_2(N)$ tests for some universal constant c). Indeed, proving that such results do indeed translate, at least for one specific algorithm for the "usual" Probabilistic Group Testing model is an important module of our proof.

Another issue is performance-related. In general, $c\mu\log_2(N)$ tests are not necessarily within a universal constant factor of the lower bounds on the number of tests required for high probability recovery. Indeed, a direct extension of known information-theoretic arguments ([3, 4, 13]) show that a natural lower bound corresponds to the entropy, $H(\mathbf{X}) = \sum_i^N H(p_i)$ where $H(p_i)$ is the binary entropy function of the vector $\mathbf{X}$ of binary random variables X_i. For the sake of completeness Theorem 1 below reproduces these arguments in our probabilistic model. It is not hard to construct distributions for the vector of random variables X_i such that the ratio between $H(\mathbf{X})$ and $\mu\log_2(N)$ is arbitrarily large. Indeed, there are some extremal instances of distribution on the population vector $\mathbf{X}$ where μ is constant but the entropy $H(\mathbf{X})$ is arbitrarily small[2]. Thus existing Probabilistic Group Testing algorithms might not be optimal and their performance is not guaranteed under "standard" input assumptions.

A. Previous Work

Some previous attempts to analyze models with prior statistic information include an interesting information-theoretic approach, shown in [17]. Although the model is different and more restrictive, they

[1] It is true that even this model is still fairly restrictive – probabilistic models with finer structure, such as correlation between "neighbouring" variables, or graph constraints, to model the effect of geography or social structures are the subject of ongoing investigation.

[2] Note that for our adaptive algorithm in III-A1, in expectation, the upper bound of number of tests stated in section III requires no restriction on the distribution of population vector $\mathbf{X}$. Nevertheless, the concentration result of our adaptive algorithm in III-A1 and the upper bound of number of tests of our non-adaptive algorithm in III-B1 require some loose conditions defined in II-A2 as *pre-partitioned model*.

provide optimal or sub-optimal algorithms for a certain choices of parameters. In particular, they deal with a particular type of prior information, where the universal set is partitioned, and within a part, all subsets of a fixed given size are uniformly distributed. For this slight generalization of traditional group-testing, they prove the existence of a non-adaptive algorithm whose average performance is information-theoretically optimal, up to a small constant factor.

The *Probabilistic Group Testing* (PGT) model, in which each item is defective i.i.d. Bernoulli(p), was considered in [6, 16, 19]. In some of these works, an interesting subclass of adaptive group-testing strategies called *Nested Test Plans* were introduced. Nested test plans are constructed in a "laminar" manner, *i.e.*, groups comprising tests are either proper subsets of prior groups, or disjoint. A recursive algorithm was given in [16, 19] to design optimal nested test plans. However, the computational complexity of this scheme is exponential in N, and also does not result in an explicit bound on the number of tests required by the algorithm. A natural lower bound stated in [16, 19] on the number of tests required equals $NH(p)$ – indeed, this is related to the information-theoretic lower bound we derive in Theorem 1.

A relationship between PGT and Huffman codes was also mentioned in [19] above. However, the Huffman-based design specified therein differs significantly from the one presented in this work – the design in [19] in general may result in group testing algorithms that require far more than the optimal number of tests.

B. Contributions

We design explicit adaptive and non-adaptive group-testing algorithms for the scenario with prior non-uniform statistics on the probability of items being defective (in an i.i.d. manner). In doing so, we discover interesting and novel connections between source codes (such as Shannon-Fano codes/Huffman codes) and adaptive group-testing algorithms. We prove that the expected number of tests required by both our adaptive and non-adaptive algorithms are information-theoretically optimal up to explicitly computed factors. Under mild assumptions on the probability distributions of the number of items, we further prove that with high probability the number of tests required is tightly concentrated around the expectation.

II. Background

A. Preliminaries

1) Model and Notations: Let $\mathcal{N} = \{X_1, X_2, \ldots, X_N\}$ denote the *universal set*, the set of N items being tested where each X_i is an independent binary random variable. Let $\mathbf{X} = (X_1, X_2, \ldots, X_N) \in \{0,1\}^N$ be the *population vector*, the initial vector for our group testing. Furthermore, we assume each *tested item* X_i can be *defective* with *a priori probability* p_i, which means that X_i takes the value 1 with probability p_i. Denote the corresponding coded vector by $\mathbf{Y} = (Y_1, Y_2, \ldots, Y_T) \in \{0,1\}^T$, namely the *result vector* that contains

the test results. The decoding process returns an output vector defined by $\hat{\mathbf{X}} = \left(\hat{X}_1, \hat{X}_2, \ldots, \hat{X}_N\right) \in \{0,1\}^N$ which is called the *recovered vector*.

In our probabilistic model, we choose to translate the sparsity requirement of Combinatorial Group Testing into the following natural *sparse property*: the *expected number of defective items* μ satisfies $\mu = \sum_{i=1}^{N} p_i \ll N$. The *average error probability*[3] $P_e \geq 0$ is defined by $P_e = \Pr[\mathbf{X} \neq \hat{\mathbf{X}}]$. In our design, an *a prior* upper bound of average error probability $\bar{P}_e$ is chosen such that $\bar{P}_e \geq P_e$, where $\bar{P}_e$ serves as a fixed baseline for the error probability varies according to different applications. Furthermore we denote the entropy of population vector by $H(\mathbf{X}) = \sum_{i=1}^{N} H(p_i)$ where $H(p_i)$ is the binary entropy function.

Our algorithms perform a sequence of measurements and guarantee that $\hat{\mathbf{X}}$ matches $\mathbf{X}$ with high probability. A test is a subset $\mathcal{S} \subseteq \mathcal{N}$ to be measured, the *testing procedure* is the collection of all tests (possibly in order). The objective is to minimize the number of tests T, given the choice of $\bar{P}_e$, that allows the reconstruction of the output vector.

2) Pre-partitioned Model: We define a partition $\mathcal{P}$ on the universal set $\mathcal{N}$, wherein the subsets satisfy some requirements. These requirements will induce a slight modification of our algorithms (for the first stage, we will test the subsets from the partition). This technicality allows us to prove a relatively acceptable bound on the performance of our algorithms. We now define the partition and the corresponding requirements.

Definition 1. *The universal set $\mathcal{N}$ is said to be a* **skewed set** *if the entropy of the population vector $H(\boldsymbol{X})$ can be bounded by*

$$H(\boldsymbol{X}) > \max\left(2\mu, \Gamma^2\right) \tag{1}$$

where the **measure factor** $\Gamma = \left\lceil \log_2\left(\log_2\left(2N/\bar{P}_e\right)\right)\right\rceil$ *is defined as a function of the upper bound $\bar{P}_e$ on the average error probability P_e and of the total number of items N. Otherwise $\mathcal{N}$ is said to be* **non-skewed**.

Definition 2. *For any non-empty subset $\mathcal{U}$ of the universal set $\mathcal{N}$, we say that $\mathcal{U}$ is a* **well-balanced subset** *if the corresponding a priori probabilities p_i of items X_i in $\mathcal{U}$ satisfy the following constraint:*

$$p_i{}^2 \leq p_j \qquad \forall X_i, X_j \in \mathcal{U}. \tag{2}$$

Furthermore, if the following constraint also satisfied,

$$\bar{P}_e/2N < p_i < 1/2 \qquad \forall X_i \in \mathcal{U}, \tag{3}$$

then we say that $\mathcal{U}$ is a **well-balanced bounded subset**. *Also, $\mathcal{U}$ is said* **bounded below by** $\bar{P}_e/2\boldsymbol{N}$ *if $p_i > \bar{P}_e/2N$; and $\mathcal{U}$ is said* **bounded above by** $1/2$ *if $p_i < 1/2$. Otherwise $\mathcal{U}$ is said to be* **unbounded**.

If we assume our universal set $\mathcal{N}$ is non-skewed, then a pre-partition into subsets $\mathcal{U}_s$ can be found

[3]Since our model is probabilistic, we ambiguously sometime use the term "error probability" stand for P_e in this paper.

using the following steps.

First we sort all the *a priori* probabilities p_i. Then we trim the universal set $\mathcal{N}$ into L disjoint subsets $\mathcal{U}_s$ with index s according to the distribution of p_i such that $\mathcal{N}$ is consists of 2 unbounded subsets and $L-2$ well-balanced bounded subsets. Note that L is determined by our chosen error probability P_e, each *a priori* probability p_i and the total number of items N. The schematic diagram Figure 1 explains this procedure.

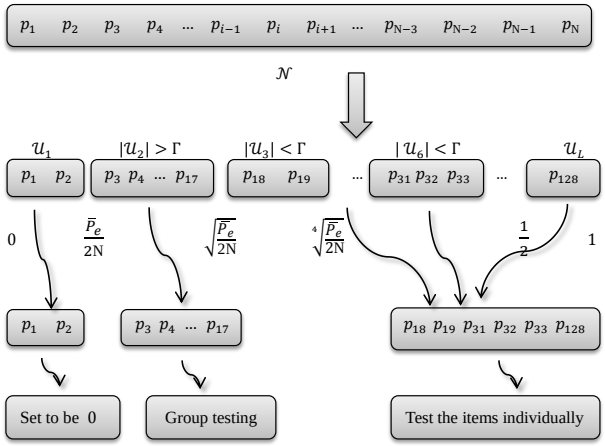


Fig. 1. This diagram depicts a partitioning procedure. For instance, two possible empty subsets $\mathcal{U}_1$ and $\mathcal{U}_L$ without bounds, while the remaining $L-2$ trimmed subsets are well-balanced bounded. The reason why $\mathcal{U}_1$ are assigned 0 directly is that the probability of $\mathcal{U}_1$ containing defective items is quite small, thus we can still get a proper upper bound with a small error probability, details are given in appendix VII VII-B,VII-D. And the value between each subset implies the theoretical boundary for the partition.

After creating the partition we classify the L subsets using the definition below.

Definition 3. *For any non-empty well-balanced subset $\mathcal{U}$ of the universal set $\mathcal{N}$, we say $\mathcal{U}$ is an* **ample subset** *if the cardinality of $\mathcal{U}$ satisfies $|\mathcal{U}| \geq \Gamma$. Otherwise we say $\mathcal{U}$ is* **not ample**.

Now for all pre-partitioned subsets $\mathcal{U}_s$, if $\mathcal{U}_s$ is ample, we regard it as a feasible subset for the group testing and define our group-testing algorithms on each such subset without disturbing others. On the other hand, for those subsets $\mathcal{U}_s$ which are not ample and the last subset $\mathcal{U}_L$ which is not bounded above by $1/2$, we combine them together and test all the items in the combined set individually; for the first subset $\mathcal{U}_1$ which is not bounded below by $\bar{P}_e/2N$, we just regard all items in $\mathcal{U}_1$ as non-defective items without doing any test. By the methodology above for our testing procedure, one can attest acceptable concentration outcomes and upper bounds for both adaptive and non-adaptive algorithms. The results are given in section III with proofs in Appendix VII.

3) Discussion on the Lower Bound: Our first result is a universal information-theoretic lower bound[4]

This theorem will be used in Section V as a simulation benchmark.

[4]This theorem is derived in appendix VII as a straightforward application of Fano's inequality (e.g. chapter 2 of [5]). Similar techniques were used in the literature (see for instance [9, 14] to derive information-theoretic lower bounds on the number of tests when the probabilities of items being defective are homogeneous.

TABLE I
FREQUENTLY USED NOTATION

Notation	Description
$\mathcal{N}$	The *universal set* of all items being tested
$\mathcal{U}$	The disjoint *pre-partitioned subsets* of the universal set $\mathcal{N}$
Ω	The laminar family of all tested subsets $\mathcal{S}_{kl_r}$ in the adaptive algorithms
N	The total number of items, $N = \lvert\mathcal{N}\rvert$
T	The number of tests used by the group-testing algorithm
L	The number of pre-partitioned subsets $\mathcal{U}_s$
Γ	The *measure factor* defined as $\Gamma = \lceil \log_2 \left(\log_2 \left(2N/\bar{P}_e \right) \right) \rceil$
M	The $T \times N$ Boolean matrix defining a group testing procedure
$\mathbf{X}$	The length-N initial *population vector* $(X_1, ...X_N)$ *population vector* where x_i are independent binary variables
$\mathbf{Y}$	The length-T binary coded *result vector* $(Y_1, ..., Y_N)$ where Y_i is the outcome of the corresponding group test
$\hat{\mathbf{X}}$	The length-N output *recovery vector* $(\hat{X}_1, ...\hat{X}_n)$ decoded from the result vector $\mathbf{Y}$
$\mathbf{p}$	The length-N real-valued probability vector $(p_1 ... p_N)$ where p_i is the *a priori* probability of X_i to be defective
$\hat{\mathbf{p}}$	The modified probability vector got from $\mathbf{p}$ by letting $\hat{p_i} = 1 - p_i/N - \mu$
P_e	The average *error probability*: $P_e = \Pr\left[\mathbf{X} \neq \hat{\mathbf{X}}\right]$
$\bar{P}_e$	The A pre-determined upper bound for *error probability*
m	The number of subsets in the same step of tests in the laminar family Ω and k is the index used for the depth of the binary tree. For example, the total number of subsets S_{kl_r} in the kth stage is m_k
g	The *group testing sampling parameter* for the testing matrix M in the non-adaptive algorithm

Theorem 1. *Any Probabilistic Group Testing algorithm with noiseless measurements whose average error probability is at most* P_e *requires at least* $(1 - P_e)\, H(\boldsymbol{X})$ *tests where* $H(\boldsymbol{X}) = \sum_{i=1}^{N} H(p_i)$.

As an immediate corollary, if all probabilities p_i are larger than $1/2$, the most efficient way to proceed is to test each element individually. Considering the disjunctive nature of measurements, it is therefore natural to test the items in the tail set $\mathcal{U}_L$ individually.

We believe that this theorem is a witness of a relationship between compression codes and group testing. It is a counterpart of the well-known data compression lower bound. Indeed, given a probability distribution, the expected length of any code is also lower bounded by the entropy $H(\mathbf{X})$ of the distribution $\mathbf{X}$. Further, sub-optimal/optimal codes such as Shannon-Fano/Huffman codes [5, 12, 15] meet this bound up to small additive factor. Some of our algorithms also employ such codes, in a different way, and meet the Probabilistic Group Testing lower bound up to multiplicative factors.

B. Adaptive Algorithms

In adaptive algorithms, the order of the tests matters since we can design later tests according to the result of previous tests. By design, our testing procedure will always satisfy the following property: if a subset $\mathcal{S}$ tested positive at stage k, then $\mathcal{S}$ will be split into two (children) subsets to be tested at stage $k + 1$. In this way, the whole testing procedures can be depicted as a tree where stages correspond to

depth. Tests in child nodes correspond to subsets of items being tested in their parent node. Leaves are individual tests, thus a path in this tree identifies a single defective item. For our purposes, the first stage will usually be dealt separately.

First we introduce an adaptive algorithm using the idea of a restricted set of test plans called *Nested Test Plan* in [16]. The algorithm is called *Nested Algorithm*. We provide different constructions.

1) Nested Algorithm BASED ON MAXIMUM ENTROPY: Suppose we know the first $k-1$ outcomes $\left(Y_1', Y_2', \ldots, Y_{k-1}'\right)$ where Y_i' is the binary result of test i.

We define the next test by choosing a subset such that $\Pr\left[Y_k = 0 | Y_{k-1} = Y_{k-1}', \ldots, Y_2 = Y_2', Y_1 = Y_1'\right]$ is closest to $1/2$ (thus locally maximizing the information learned at each stage about the input vector).

In general getting a probability of exactly $1/2$ is not possible due to the fact that the probability vector has arbitrary entries. Quantifying the impact of these "quantization errors", both in terms of the probability of error, and the number of tests required, is one of the major tasks required in our proof techniques. The full details are given in the third part III and the proof in the appendix VII (see VII-B).

In practice, we choose the subsets being tested such that the probability they contain a defective item is close to $1/2$, given that the previous tests were positive. This imply, by Bayes rule, that the product of $(1-p_i)$ has to be close to a certain value that we will explicit.

2) Nested Algorithm WITH SOURCE CODES : The second type of adaptive algorithms is based on Shannon-Fano/Huffman source codes. Instead of constructing the tree one step at a time, we do the partition at the beginning to make sure that the source coding process can be done correctly within each subset. Then set the weight w_i we need as p_i and the testing tree can be constructed before we doing the group testing. An similar upper bound is achieved using Shannon-Fano/Huffman coding trees with lengths of codewords l_i bounded by $\lceil \log_2 (1/p_i) \rceil$. A more detailed discussion is provided in section III-B1 and section VII-B.

Figure 2 partially depicts the testing tree of the *Nested Algorithm* describing also typical structure describing the criteria to form our laminar family Ω.

3) CONCENTRATION: It remains to show that the actual number of steps in these algorithms is close to the expected value, that is: concentrate the number of tests T required. Our original model of prior is too general, preventing us from having a general concentration result with the technique we employ. To solve this, we add an extra assumption at the very first stage and assume $\mathcal{N}$ is non-skewed according to definition 1. Then a pre-partitioned testing pool which is comprised of L different subsets can be constructed.

Then based on the pre-partitioned model, we're going to test the ample subsets which are large enough. Moreover, another problem is that the summation of the *a priori* probabilities may not be large enough within first several ample subsets. To deal with this, we combine the first several subsets until the summation of *a priori* probabilities is more than one-half. The total number of subsets we need to combine turns to be bounded above by a relatively small value with details of proof in VII-B.

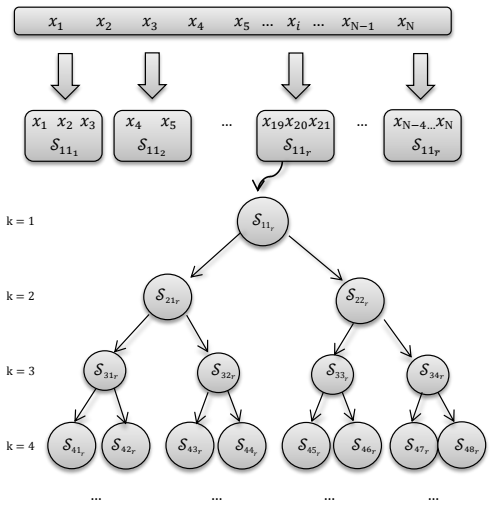


Fig. 2. Graphical description of the *Nested Algorithm* without error estimation, first we start with the initial set $\mathbf{X}$ containing X_1 up to X_N. Then do the partition we have several subsets from $\mathcal{S}_{11_1}$ up to $\mathcal{S}_{11_{\bar{r}}}$ satisfying $\prod_{i=1}^{3}(1-p_i)=\frac{1}{2}$ and so on in this particular example. The construction of testing tree follows the two method: *ME* and *S/H*.

C. Non-adaptive Algorithm

Non-adaptive algorithms require the testing procedure to be fixed in advance. Therefore they might be less powerful than adaptive algorithms, but now the tests can be done in parallel, which is convenient for hardware design.

For the design of our non-adaptive algorithms, we represent the tests as a $T \times N$ Boolean matrix *group-testing matrix* M. Each row of M corresponds to a measurement, and each column corresponds to a single item to be tested. In this way we have the the population vector $\mathbf{X}$ and the result vector $\mathbf{Y}$ satisfy

$$\mathbf{Y} = M\mathbf{X}^{\intercal}.$$

We first consider an algorithm so-called *Coupon Collector Algorithm* adapted from the traditional one in [4]. The group-testing matrix M is defined as follows. A *group testing sampling parameter* g is chosen by optimization which is fixed by the probability vector $\mathbf{p}$. The ith row of M is then obtained by sampling probability vector $\hat{\mathbf{p}} = (\hat{p}_1, \ldots, \hat{p}_N)$, where $\hat{p}_i = (1-p_i)/(N-\mu)$, exactly g times with replacement (for convenience), and setting $M_{i,j} = 1$ if j is sampled (at least once) during this process, and zero otherwise [4].

Using this design, we show that the testing procedure requires only $4(1+\delta)e\mu \ln N$ tests with high probability.

However, this bound is often worse than our information-theoretic lower bound, and only behaves approximately when the distribution on items x_i is close to uniform, namely the p_is do not differ much. It is thus reasonable to assume the universal set $\mathcal{N}$ is non-skewed and use a block design, similarly to the concentration part of *Nested Algorithm*. That is, have a set of pre-partitioned subsets containing L subsets $\mathcal{U}_s$.

Then we have the matrix representation M for the whole testing procedure can be partitioned into

$L-1$ sub-matrices M_s which are all bounded below by $\bar{P}_e/2N$, and such that

$$M = \bigoplus_{s=2}^{L} M_s,$$

where $\bigoplus$ is the direct sum.

In the *Block Algorithm*, we will assume the existence of a suitable pre-partitioned and use, as a sub-algorithm, the *Coupon Collector Algorithm* for each subset $\mathcal{U}_s$, for which we control the testing complexity and error probability.

We depict the matrix M of the *Block Algorithm* in Figure 3.

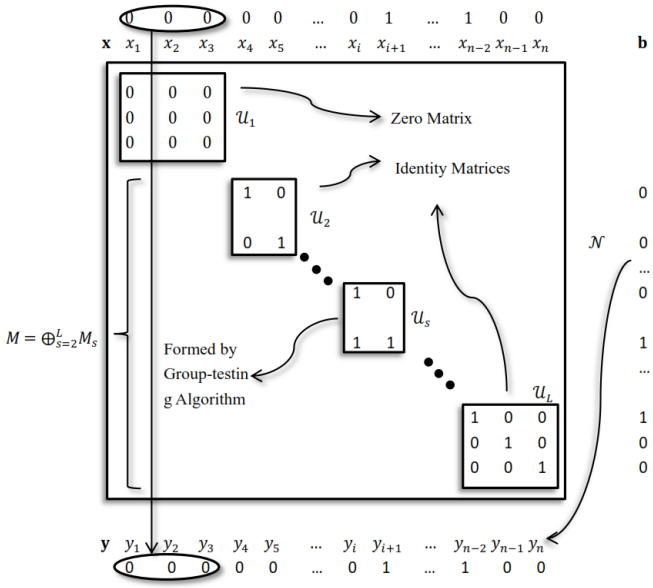


Fig. 3. Graphical description of *Block Algorithm*, where the testing matrix are defined as this particular example. The population vector is $\mathbf{X}$ which is encoded to $\mathbf{Y}$ and decoded to $\hat{\mathbf{X}}$ by doing the pre-partition. The decoding process contains three different cases: For each ample subset $\mathcal{U}_s$, group testing procedure is done separately; for $\mathcal{U}_1$, we assign it with a zero matrix which means there is no tests for it since all items are set to be 0 directly; moreover, for items in those subsets which are not ample or in $\mathcal{U}_L$, we test them individually.

III. Main Results

A. Adaptive Algorithms

First we introduce an adaptive algorithm using the idea of a restricted set of test plans called *Nested Test Plan* in [16]. The algorithm is called *Nested Algorithm*. We provide different constructions.

1) Nested Algorithm based on Maximum Entropy: The first construction is based on the maximization of entropy. Namely, the conditional entropy that remains after each test which is a relatively good approximation of the optimal algorithm.

a) First Stage: In the first stage, we check if $\mu = \sum_{i=1}^{N} p_i$ is smaller than the upper bound of average error probability $\bar{P}_e$, if so we just return $\hat{\mathbf{X}} = \mathbf{0}$. Otherwise, we partition the universal set $\mathcal{N}$ into contiguous

subsets $\mathcal{S}_{11_r}$ indexed by r, greedily: The partition is chosen such that $\Pr\left[\exists X_j \in \mathcal{S}_{11_r} \text{ s.t. } X_j = 1\right]$ is the closest to $1/2$, *i.e.*:

$$\min \left| \prod_{X_j \in \mathcal{S}_{11_r}} (1 - p_j) - \frac{1}{2} \right|$$
$$\text{subject to} \quad p_j < 1, \text{ where } j = 1, 2, \ldots, N.$$

b) Second Stage: In the second stage, negative tests ensure no item is defective, we can thus forget about the corresponding subsets. If the test is positive, we divide the corresponding subset $\mathcal{S}_{11_r}$ into two smaller subsets $\mathcal{S}_{21_r}$, $\mathcal{S}_{22_r}$ such that $\Pr\left[\exists X_j \in \mathcal{S}_{21_r} \text{ s.t. } X_j = 1 | b_1 = 1\right]$ is the closest to $1/2$, *i.e.*,

$$\min \left| \frac{1 - \prod_{X_j \in \mathcal{S}_{21_r}} (1 - p_j)}{1 - \prod_{X_j \in \mathcal{S}_{11_r}} (1 - p_j)} - \frac{1}{2} \right|$$
$$\text{subject to} \quad p_j < 1, \text{ where } j = 1, 2, \ldots, N.$$

c) Later Stages: Similarly, in the kth stage, we forget about subsets that tested negative in the previous stage, and split each remaining subset as

$$\min \left| \frac{1 - \prod_{X_j \in \mathcal{S}_{kl_r}} (1 - p_j)}{1 - \prod_{X_j \in \mathcal{S}_{(k-1)l_r}} (1 - p_j)} - \frac{1}{2} \right|$$
$$\text{subject to} \quad p_j < 1,$$

where $j = 1, 2, \ldots, N$, $\forall l = 1, 3, \ldots, 2^{k-1} - 1$.

2) NESTED ALGORITHM WITH SOURCE CODES: Instead of using the previous binary test trees, we use a source code for each subset. From Kraft's inequality, this is possible if the probability of each subset is less than 1.

a) First Stage: We proceed similarly to the previous one except that we require the product of $(1 - p_i)$ in each subset being strictly larger than half. The partition is defined by:

$$\min \left| \prod_{X_j \in \mathcal{S}_{11_r}} (1 - p_j) - \frac{1}{2} \right|$$
$$\text{subject to} \quad p_j < 1, \prod_{X_j \in \mathcal{S}_{11_r}} (1 - p_j) \geq \frac{1}{2},$$

where $j = 1, 2, \ldots, N$.

b) Later Stages: Next, within each subset $\mathcal{S}_{11_r}$ we have $\prod_{X_j \in \mathcal{S}_{11_r}} (1 - p_j) \geq 1/2$. This implies that $\sum_{X_j \in \mathcal{S}_{11_r}} p_i \leq 1$.

Then for each subset $\mathcal{S}_{11_r}$, we set the weights w_i as the corresponding p_i and apply Shannon-Fano

coding, Huffman coding in [12, 15] or any source codes to construct the testing tree.

B. Non-adaptive Algorithms

1) BLOCK ALGORITHM: In our non-adaptive algorithms, we represent the tests as a $T \times N$ Boolean matrix *group-testing matrix* M. Each row of M corresponds to a measurement, and each column corresponds to a single item to be tested. In this way the population vector $\mathbf{X}$ and the result vector $\mathbf{Y}$ satisfy: $\mathbf{Y} = M\mathbf{X}^{\intercal}$.

We first consider an algorithm called *Coupon Collector Algorithm* adapted from the traditional one in [4]. The group-testing matrix M is defined as follows. A *group testing sampling parameter* g is chosen by optimization given the probability vector $\mathbf{p}$. The ith row of M is then obtained by sampling probability vector $\hat{\mathbf{p}} = (\hat{p}_1, \ldots, \hat{p}_N)$, where $\hat{p}_i = (1 - p_i) / (N - \mu)$, exactly g times with replacement (for convenience), and setting $M_{i,j} = 1$ if j is sampled (at least once) during this process, and zero otherwise [4]. Using this design, we show our testing procedure requires only $4(1+\delta)e\mu \ln N$ tests with high probability. However, this bound is often worse than our information-theoretic lower bound, and only matches the bound when the distribution on items X_i is close to uniform, namely the p_is do not differ much. It is thus reasonable to assume again that our universal set $\mathcal{N}$ is non-skewed and use a block design, similarly to the concentration part of *Nested Algorithm* discussed in IV-A3. That is, we have a set of pre-partitioned subsets containing L subsets $\mathcal{U}_s$. Then the matrix representation M for the whole testing procedure can be partitioned into $L-1$ sub-matrices M_s corresponding to subsets bounded below by $\bar{P}_e/2N$, and such that $M = \bigoplus_{s=2}^{L} M_s$, where $\bigoplus$ is the direct sum.

Suppose the universal set $\mathcal{N}$ is non-skewed and thus has a pre-partition. Each ample subset of the partition will be considered separately. We use the following steps to specify the corresponding testing sub-matrix M_s:

First, according to the given *a priori* probability vector $\mathbf{p}$, compute the corresponding $\hat{\mathbf{p}} = (\hat{p}_1, \ldots, \hat{p}_N)$ where $\hat{p}_i = (1 - p_i) / (N - \mu)$ and the *sampling parameter* g by $g^* = -\left[\ln\left(\sum_{i=1}^{N} \hat{p}_i (1 - p_i)\right)\right]^{-1}$. Then for each testing sub-matrix M_s, in each row we choose the items with replacement g^* times according to the probability distribution vector $\hat{\mathbf{p}}$, and form the testing matrix M as discussed above.

IV. UPPER BOUNDS AND ANALYSIS

In this section we state and give proof sketches of our main results: The upper bounds on number of tests of our algorithms specified in section III above, More details can be found in the Appendix VII.

A. Nested Algorithm

Theorem 2. *The Nested Algorithm needs at most* $2H(\boldsymbol{X}) + 2\mu$ *tests in expectation.*

1) NESTED ALGORITHM BASED ON MAXIMUM ENTROPY: Suppose we know the first $l-1$ outcomes $\left(Y_1', Y_2', \ldots, Y_{l-1}'\right)$ where Y_i' is the binary result of the ith test. We define the next test by choosing a subset such that $\Pr\left[Y_l = 0 | Y_{l-1} = Y_{l-1}', \ldots, Y_2 = Y_2', Y_1 = Y_1'\right]$ is closest to $1/2$ (thus locally maximizing the information learned at each stage about the input vector). In general, achieving a probability of exactly $1/2$ is not always possible due to the fact that the probability vector has arbitrary entries.

In practice, we choose the subsets being tested such that the probability they contain a defective item is close to one-half, given that the previous tests were positive. This imply, by Bayes rule, that the product of $(1-p_i)$ has to be close to a certain value that we will explicit.

Such a testing procedure behaves as a "testing tree". Now if we ignore the "quantization errors": *i.e.*, always assume that the probabilities of the previous outcomes negative or positive are exactly the same[5], then such a construction implies, $p_i \leq (1/2)^k$ for every k-th stage of tests and the length of branch of the "testing tree" for each item X_i is bounded by $l_i \leq \lceil \log_2 (1/p_i) \rceil$. Hence the expected number of tests T we need is bounded by $E(T) \leq \sum_{i=1}^{N} 2 l_i p_i \leq 2H(\mathbf{X}) + 2\mu$.

2) NESTED ALGORITHM WITH SOURCE CODES : The second type of adaptive algorithms is based on Shannon-Fano/Huffman source codes. Instead of constructing the tree one step at a time, we use a partition which allows source coding within each subset. For coding, we use the weights $w_i = p_i$, the "testing tree" can be constructed before the implementing the group testing. A similar upper bound is achieved using Shannon-Fano/Huffman coding trees where the length of codeword l_i is bounded by $\lceil \log_2 (1/p_i) \rceil$. Hence by the same argument as above for *Maximum Entropy* construction, it follows that $E(T) \leq 2H(\mathbf{X}) + 2\mu$.

3) CONCENTRATION: If we use the pre-partitioned model as defined in II-A2, the following result holds.

Theorem 3. *If the universal set $\mathcal{N}$ is non-skewed, then with $\delta \geq 2e-1$ and average error probability $P_e = (N/\mu)^{-(1+\delta)\mu} + \bar{P}_e/2$, the Nested Algorithm requires no more than $4(1+\delta)(\Gamma+3)H(\mathbf{X})$ tests.*

It remains to show that the actual number of steps in these algorithms is close to the expected value, that is: concentrate the number of tests T required. Our original model of priors is too general, preventing us from having a general concentration result with the technique we employ. To solve this, we add an extra assumption at the very first stage such that $\mathcal{N}$ is non-skewed according to Definition 1. Then based on the pre-partitioned model, we test the ample subsets which are large enough. Moreover, we may combine the first several subsets until the sum of *a priori* probabilities is greater than one-half. The total number of subsets we need to combine turns out to be bounded above by a relatively small value. The proof relies on the ample and well-balanced bounded requirements for subsets. The maximum length of

[5]Note that our algorithm actually performs better, since we account for the "quantization errors" in each stage of tests. Thus our current analysis is dominated by the real *Nested Algorithm*.

branch l_{max} within each "testing tee" satisfies $l_{max} \leq 2l_i$ for all $i \in \mathcal{U}_s$. The results follows from the above facts and the Chernoff bound in [11].

B. Block Algorithm

Theorem 4. *If the universal set $\mathcal{N}$ is bounded above by $1/2$, then with average error probability at most $P_e = N^{-\delta}$, the Coupon Collector Algorithm requires no more than $4e\,(1+\delta)\,\mu \ln N$ tests.*

Theorem 5. *If the universal set $\mathcal{N}$ is bounded above by $1/2$ and non-skewed, then with average error probability at most $P_e \leq 2\Gamma^{-\delta+1} + \bar{P}_e/2$, the Block Algorithm requires no more than $(12e+2)\,(1+\delta)\,H(\boldsymbol{X})$ tests.*

1) BLOCK ALGORITHM: In the *Block Algorithm*, we will assume the existence of a suitable pre-partitioned and use, as a sub-algorithm, the *Coupon Collector Algorithm* for each subset $\mathcal{U}_s$, for which we control the testing upper bound and average error probability. The proof of Theorem 4 involves a general version of *Coupon Collector Problem* which appears in Arnon Boneh *et al.* [2]. The average error probability is controlled by the Chernoff bound again. To analyze the performance of *Block Algorithm*, notice that the probability distribution among each subset $\mathcal{U}_s$ to be tested satisfies ${p_i}^2 \leq p_j$ for all $X_i, X_j \in \mathcal{U}_s$. Thus the upper bound from Theorem 4 reduces to the entropy $H(\mathbf{X})$ of population vector $\mathbf{X}$ up to some constant factor. Moreover, the average error probability is controlled by the union bound of each error probability from the subsets to be tested.

V. EXPERIMENTAL RESULTS

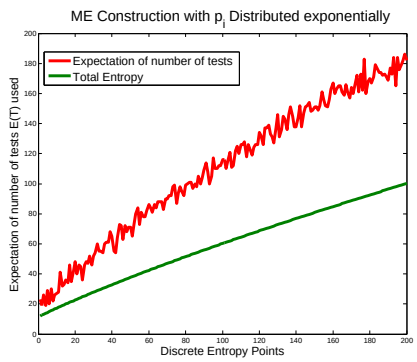
We provide experimental simulation results for both *Nested Algorithm(NA)* and *Coupon Collector Algorithm(CCA)*. We considered three different extremal kinds of probability vectors $\mathbf{p}$: uniform, linear, and exponential.

For *NA*, both Maximum Entropy and Huffman Coding constructions were simulated. We used 200 different points of entropy $H(\mathbf{X})$. As a result we can see the $E(T)$ computed from 200 trials at each entropy point looks linear in $H(\mathbf{X})$ where the coefficient is close to 2 as shown in figs. 4(a) to 4(c) and 5(a) to 5(c). Moreover, the experiment is based on standard *NA* without using pre-partitioned model to ensure the concentration results.

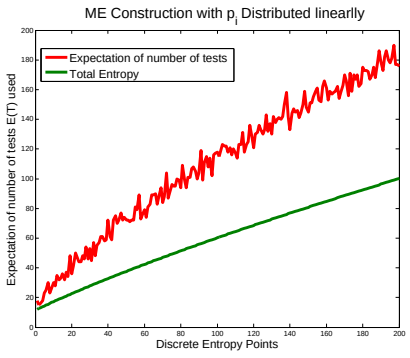
For *CCA*, based on the different types of distribution of $\mathbf{p}$, we tested three different values of μ and computed the corresponding error probability in 200 trials. We compared this error probability with the theoretic error probability P_e as shown in figs. 6(a) to 6(c).

VI. CONCLUSION AND DISCUSSION

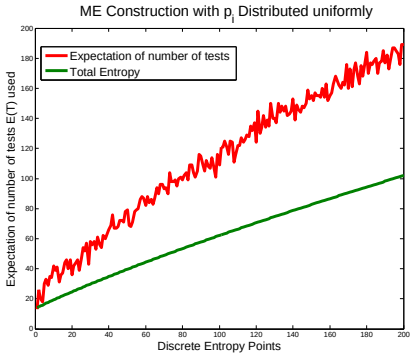
We studied a novel model of Probabilistic Group Testing and provided two types of algorithms. Experimental results tend to show concentration of our theorems on the expected number of tests.


ME Construction with p_i Distributed exponentially
Expectation of number of tests
Total Entropy
Expectation of number of tests E(T) used
Discrete Entropy Points

(a) Exponentially distributed $\mathbf{p}$ with N=1000 at 200 different entropy points with $E(T)$ on each point calculated by 200 trials

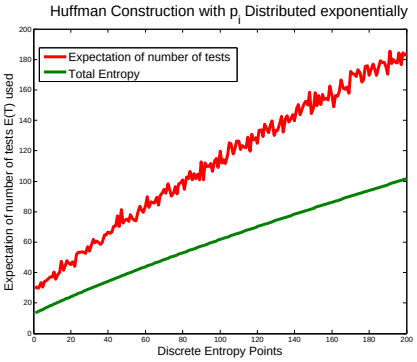

ME Construction with p_i Distributed linearly
Expectation of number of tests
Total Entropy
Expectation of number of tests E(T) used
Discrete Entropy Points

(b) Linearly distributed $\mathbf{p}$ with N=1000 at 200 different entropy points with $E(T)$ on each point calculated by 200 trials

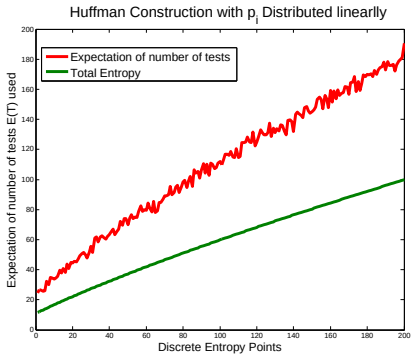

ME Construction with p_i Distributed uniformly
Expectation of number of tests
Total Entropy
Expectation of number of tests E(T) used
Discrete Entropy Points

(c) Uniformly distributed $\mathbf{p}$ with N=1000 at 200 different entropy points with $E(T)$ on each point calculated by 200 trials

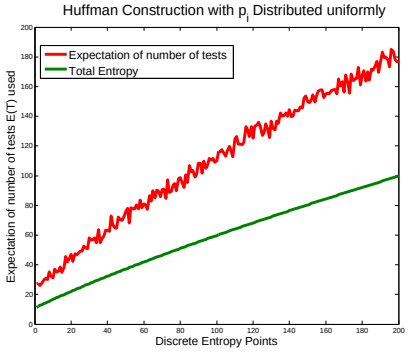
Fig. 4. Experiment results.


Huffman Construction with p_i Distributed exponentially
Expectation of number of tests
Total Entropy
Expectation of number of tests E(T) used
Discrete Entropy Points

(a) Exponentially distributed $\mathbf{p}$ with N=1000 at 200 different entropy points with $E(T)$ on each point calculated by 200 trials

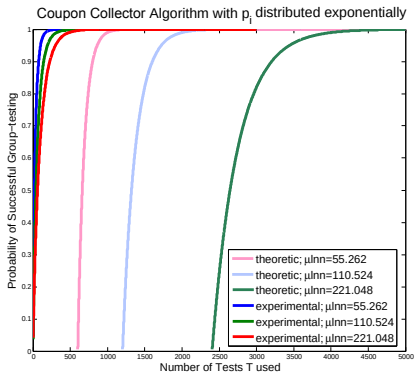

Huffman Construction with p_i Distributed linearly
Expectation of number of tests
Total Entropy
Expectation of number of tests E(T) used
Discrete Entropy Points

(b) Linearly distributed $\mathbf{p}$ with N=1000 at 200 different entropy points with $E(T)$ on each point calculated by 200 trials

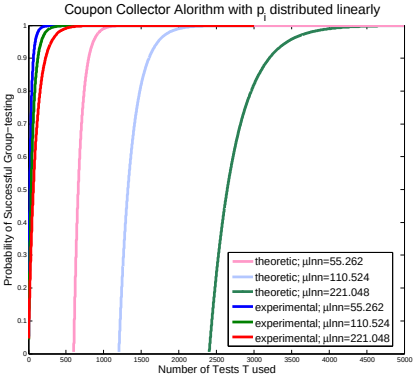

Huffman Construction with p_i Distributed uniformly
Expectation of number of tests
Total Entropy
Expectation of number of tests E(T) used
Discrete Entropy Points

(c) Uniformly distributed $\mathbf{p}$ with N=1000 at 200 different entropy points with $E(T)$ on each point calculated by 200 trials

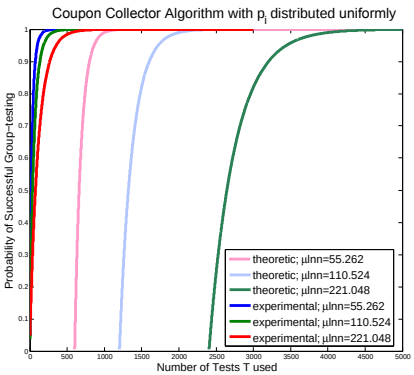
Fig. 5. Experiment results.



(a) The probability of successful group testing as a function of number of tests T with exponentially distributed $\mathbf{p}$ and $N = 1000$, $\mu = 8, 16, 32$ sampled by 200 trials



(b) The probability of successful group testing as a function of number of tests T with linearly distributed $\mathbf{p}$ and $N = 1000$, $\mu = 8, 16, 32$ sampled by 200 trials



(c) The probability of successful group testing as a function of number of tests T with uniformly distributed $\mathbf{p}$ and $N = 1000$, $\mu = 8, 16, 32$ sampled by 200 trials

Fig. 6. Experiment results.

For the sake of proofs, both adaptive and non-adaptive algorithm use a less-universal assumption for the convenience of analysis. In practice, this assumption is not too demanding since we can easily find a pre-partition for the testing pool and exclude extreme probabilities by testing items with such p_i

individually. In our analysis of the non-adaptive algorithm based on the noiseless model, the choice of $\hat{\mathbf{p}}$ is acceptable but not optimal.

Other more general models involving joint probabilities between each item X_i seems to be more attractive and useful, yet more complex to analyse, this is the subject of on-going work. Our new model encapsulate the previous combinatorial model, and our algorithms provide similar encoding complexity. This makes us believe our new model is a natural generalisation of the traditional model.

It is also worth noting that for compressive sensing there are already a series analyses considering sparse signal with prior information and some weighted l_1 minimization recovery algorithm was demonstrated to have advantages over the conventional one, see [1].

REFERENCES

[1] M Amin Khajehnejad, Weiyu Xu, A Salman Avestimehr, and Babak Hassibi. Weighted 1 minimization for sparse recovery with prior information. In *Information Theory, 2009. ISIT 2009. IEEE International Symposium on*, pages 483–487. IEEE, 2009.

[2] Arnon Boneh and Micha Hofri. The coupon-collector problem revisited. 1989.

[3] Chun Lam Chan, Pak Hou Che, Sidharth Jaggi, and Venkatesh Saligrama. Non-adaptive probabilistic group testing with noisy measurements: Near-optimal bounds with efficient algorithms. In *Communication, Control, and Computing (Allerton), 2011 49th Annual Allerton Conference on*, pages 1832–1839. IEEE, 2011.

[4] Chun Lam Chan, Sidharth Jaggi, Venkatesh Saligrama, and Samar Agnihotri. Non-adaptive group testing: Explicit bounds and novel algorithms. In *Information Theory Proceedings (ISIT), 2012 IEEE International Symposium on*, pages 1837–1841. IEEE, 2012.

[5] Thomas M Cover and Joy A Thomas. *Elements of information theory*. John Wiley & Sons, 2012.

[6] Robert Dorfman. The detection of defective members of large populations. *The Annals of Mathematical Statistics*, 14(4):436–440, 1943.

[7] Ding Zhu Du and Frank Hwang. *Combinatorial group testing and its applications*. World Scientific, 1993.

[8] Dingzhu Du and Frank Hwang. *Pooling designs and nonadaptive group testing: important tools for DNA sequencing*, volume 18. World Scientific Pub Co Inc, 2006.

[9] A.G. D'yachkov. Lectures on designing screening experiments. *Lecture Note Series 10, Combinatorial and Computational Mathematics Center, Pohang University of Science and Technology (POSTECH)*, page 112, Feb 2004.

[10] Michael T Goodrich and Daniel S Hirschberg. Improved adaptive group testing algorithms with applications to multiple access channels and dead sensor diagnosis. *Journal of Combinatorial Optimization*, 15(1):95–121, 2008.

[11] Torben Hagerup and Christine Rüb. A guided tour of chernoff bounds. *Information processing letters*, 33(6):305–308, 1990.

[12] David A Huffman. A method for the construction of minimum-redundancy codes. *Proceedings of the IRE*, 40(9):1098–1101, 1952.

[13] Dmitry Malioutov and Mikhail Malyutov. Boolean compressed sensing: Lp relaxation for group testing. In *Acoustics, Speech and Signal Processing (ICASSP), 2012 IEEE International Conference on*, pages 3305–3308. IEEE, 2012.

[14] M. B. Malyutov. Separating property of random matrices. *Mat. Zametki*, 23:155–167, 1978.

[15] Claude Elwood Shannon. A mathematical theory of communication. *ACM SIGMOBILE Mobile Computing and Communications Review*, 5(1):3–55, 2001.

[16] Milton Sobel and Phyllis A Groll. Group testing to eliminate efficiently all defectives in a binomial sample. *Bell System Technical Journal*, 38(5):1179–1252, 1959.

[17] DC Torney, F Sun, and WJ Bruno. Optimizing nonadaptive group tests for objects with heterogeneous priors. *SIAM Journal on Applied Mathematics*, 58(4):1043–1059, 1998.

[18] Tadashi Wadayama. An analysis on non-adaptive group testing based on sparse pooling graphs. *arXiv preprint arXiv:1301.7519*, 2013.

[19] Jack Wolf. Born again group testing: Multiaccess communications. *Information Theory, IEEE Transactions on*, 31(2):185–191, 1985.

VII. Appendix

A. Proof of Theorem 1

Proof: The input vector, noiseless result vector and estimated input vector form a Markov chain $\mathbf{X} \to \mathbf{Y} \to \hat{\mathbf{X}}$. Then we have

$$H(\mathbf{X}) = H\left(\mathbf{X}|\hat{\mathbf{X}}\right) + I\left(\mathbf{X};\hat{\mathbf{X}}\right). \tag{4}$$

Define an error random variable e such that

$$e = \begin{cases} 1, & \text{if } \hat{\mathbf{X}} \neq \mathbf{X} \\ 0, & \text{if } \hat{\mathbf{X}} = \mathbf{X}. \end{cases}$$

By Fano's inequality, we can bound the conditional entropy as

$$\begin{aligned} H\left(\mathbf{X}|\hat{\mathbf{X}}\right) =& H\left(e, \mathbf{X}|\hat{\mathbf{X}}\right) && (5)\\ =& H\left(e|\hat{\mathbf{X}}\right) + \Pr\left[e=0\right] H\left(\mathbf{X}|\hat{\mathbf{X}}, e=0\right) + \\ & \Pr\left[e=1\right] H\left(\mathbf{X}|\hat{\mathbf{X}}, e=1\right) && (6)\\ \leq& H\left(P_e\right) + P_e H\left(\mathbf{X}\right). && (7) \end{aligned}$$

Also we have $I\left(\mathbf{X};\hat{\mathbf{X}}\right) \leq H\left(\mathbf{Y}\right) \leq \log_2 |\mathbf{Y}| = T$ by the data-processing inequality. Hence we obtain that

$$T \geq \left(1 - P_e\right) H\left(\mathbf{X}\right).$$

■

B. Proof of Theorem 2 and Theorem 3

Proof: We will prove the expectation bound for both Maximum Entropy-based construction (ME) and Shannon-Fano/Huffman Coding-based construction (S/H).

First, consider the *a priori* probabilities p_i of items that are involved in a test at stage k. For the ME, the group construction implies

$$p_i \leq \left(\frac{1}{2}\right)^k.$$

The length of branch l_i for each *a priori* probability p_i is bounded by

$$l_i \leq \left\lceil \log_2 \frac{1}{p_i} \right\rceil. \tag{8}$$

Note that (8) also holds for Shannon-Fano coding [15]. To justify Shannon-Fano coding is well-defined, we first introduce Lemma 1.

Lemma 1. *Let k be a positive integer. If $0 < p_i < 1$ for $1 \leq i \leq k$ and $\prod_{i=1}^{k}\left(1-p_i\right) \geq 1/2$, then $\sum_{i=1}^{k} p_i \leq 1$.*

Proof: Given $\prod_{i=1}^{k}\left(1-p_i\right) \geq 1/2$, or equivalently,

$$\prod_{i=1}^{k} \frac{1}{1-p_i} \leq 2. \tag{9}$$

(9) can then be expanded by geometric sum as

$$\begin{aligned} 2 \geq& \prod_{i=1}^{k}\left(\sum_{j=0}^{\infty} {p_i}^j\right)\\ \geq& 1 + \sum_{i=1}^{k} p_i, \end{aligned}$$

which yields the result $\sum_{i=1}^{k} p_i \leq 1$.

■

One thing remains to be shown is that under the partition for each subset $\mathcal{S}_{11_r}$ such that

$$\prod_{X_j \in \mathcal{S}_{11_r}} (1 - p_j) \geq \frac{1}{2}, \tag{10}$$

then the S/H is well-defined.

Note (10) is the construction requirement of the first stage. By Lemma 1, we have the Shannon-Fano/Huffman coding procedure is well-defined since the summation of *a priori* probabilities within each subset is smaller or equal to 1.

Therefore, we can bound the expected number of tests E[T] as

$$\begin{aligned} E[T] &\leq \sum_{i=1}^{N} 2 p_i l_i && (11) \\ &\leq \sum_{i=1}^{N} 2 p_i \left(\log_2 \frac{1}{p_i} + 1 \right) && (12) \\ &\leq 2H(\mathbf{X}) + 2\mu, && (13) \end{aligned}$$

where μ is the summation of all *a priori* probabilities and (11) comes from our testing procedure such that a positive testing outcome, implies two more tests for both its children.

For the second part of the result, we must show that T concentrates properly whenever the universal set $\mathcal{N}$ is non-skewed and hence we can construct the Pre-partitioned Model.Moreover, each individual group in the Pre-partitioned Model need to be made large enough to have a good concentrated performance, according to law of large numbers. Then in order to do so, we need to conflate some small subsets together such that in the combined subset $\mathcal{U}$ we have $\sum_{i \in \mathcal{U}} p_i \geq \frac{1}{2}$, which yields an acceptable concentration result.

Hence, the maximum number Λ of the subsets we need to combine is bounded by

$$\Gamma \left(\frac{\bar{P}_e}{2N} \right)^{\left(\frac{1}{2}\right)^{\Lambda}} \leq \frac{1}{2}. \tag{14}$$

Since we always have $\Gamma > 1$, we can deduce the following from (14) such that

$$\Lambda < \Gamma, \tag{15}$$

which implies the conflation process is actually well-defined.

Within each ample subset $\mathcal{U}_s$, we denote the corresponding population vector by $\mathbf{X}_s$ and the summation of the *a priori* probabilities by μ_s. Since the subsets being tested are ample and well-balanced bounded, let $p_{\max} = \max_{i \in \mathcal{U}_s} p_i$ we have

$$l_i \leq 2 l_{\max} \quad \forall i \in \mathcal{U}_s. \tag{16}$$

Thus by (15) and (16) for the combined subsets $\mathcal{U}_2 \bigcup \mathcal{U}_3 \bigcup \ldots \bigcup \mathcal{U}_\Lambda$ we have

$$l_i \leq 2^\Gamma l_{\max} \quad \forall i \in \mathcal{U}_2 \bigcup \mathcal{U}_3 \bigcup \ldots \bigcup \mathcal{U}_\Lambda. \tag{17}$$

Hence from (17) we assume $\delta \geq 2e-1$ and the Chernoff Bound [11] gives

$$\begin{aligned} &\Pr\left[T > 4(1+\delta)\left((\Gamma+2)\mu + H\left(\mathbf{X}\right)\right)\right] \\ &< 2^{-(1+\delta)H(\mathbf{X})}. \end{aligned} \tag{18}$$

And using log-sum inequality we can bound the entropy $H\left(\mathbf{X}\right)$ by the following:

$$\begin{aligned} H\left(\mathbf{X}\right) &> \sum_{i\in\mathcal{U}} p_i \log_2 \frac{1}{p_i} \\ &> \frac{1}{2}\mu \log_2 \frac{N}{\mu}. \end{aligned} \tag{19}$$

Then combine (18) and (19) we have

$$\begin{aligned} &\Pr\left[T > 4(1+\delta)(\Gamma+3)H\left(\mathbf{X}\right)\right] \\ &< 2^{-(1+\delta)H(\mathbf{X})} \\ &< (N/\mu)^{-(1+\delta)\mu} \end{aligned} \tag{20}$$

where (20) is a direct result of (19). Then consider the total error probability for the group testing procedure, for $T > 4(1+\delta)(\Gamma+3)H\left(\mathbf{X}\right)$ the average error probability P_e satisfies

$$P_e < (N/\mu)^{-(1+\delta)\mu} + \bar{P}_e/2.$$

■

C. Proof of Theorem 4

Proof: The proof approach is based on that of Thoerem 3 in [3]. Our goal is to efficiently identify all non-defective items in the universal set $\mathcal{N}$. Here we map the problem to Coupon Collector's Problem. Non-defective items are the coupons. The set of negative tests which directly reveal non-defective items can be viewed as a chain of coupon collection.

Then for each row, we assume a fixed *group testing sampling parameter* g such that the sampling process are conducted exactly g times for each row. And we use a non-uniform sampling distribution $\hat{\mathbf{p}}$ to draw the coupons. Hence the probability of outcome 0 for each group testing process is $\left(\sum_{i=1}^{N} \hat{p}_i\left(1-p_i\right)\right)^g$ and in total we have Tg times of selecting the coupons, namely the non-defective items from the universal set $\mathcal{N}$. Thus we describe a test as a length-g sequence of selection and when a collector obtains a full set of coupons, the number of coupons collected should be at least the stopping time $\mathcal{T}$. In expectation, we can

summarize the following equation:

$$Tg\left(\sum_{i=1}^{N}\hat{p}_i\left(1-p_i\right)\right)^{g}\geq E[\mathcal{T}]. \tag{21}$$

For items being drawn with non-uniform distribution $\hat{\mathbf{p}}$, [2] suggests that the expected stopping time $E[\mathcal{T}]$ is given by

$$E[\mathcal{T}]=\sum_{r=1}^{N}(-1)^{r+1}\sum_{1\leq i_1<\cdots<i_r\leq N}\frac{1}{\hat{p}_{i_1}+\hat{p}_{i_2}+\cdots+\hat{p}_{i_r}}. \tag{22}$$

Lemma 2. *Let $n\in\mathbb{Z}^{+}$, we have*

$$\sum_{r=1}^{n}(-1)^{r-1}\binom{n}{r}\frac{1}{r}=\sum_{r=1}^{n}\frac{1}{r}.$$

Proof:

$$\begin{aligned}\sum_{r=1}^{n}\frac{1}{r}&=\int_0^1\frac{1-s^n}{1-s}ds &(23)\\ &=\int_0^1\frac{1-(1-t)^n}{t}dt &(24)\\ &=\int_0^1\left[\sum_{r=1}^{n}(-1)^{r-1}\binom{n}{r}t^{r-1}\right]dt &(25)\\ &=\sum_{r=1}^{n}(-1)^{r-1}\binom{n}{r}\frac{1}{r},\end{aligned}$$

where (23) follows from the expansion of geometric sum, (24) follows from substituting $s=1-t$, and (25) follows from binomial theorem. ■

Let $\mu=\sum_{i=1}^{N}p_i$. (21) can be further computed as

$$\begin{aligned}E[\mathcal{T}]&=(N-\mu)\sum_{r=1}^{N}(-1)^{r+1}\\ &\qquad\sum_{1\leq i_1<\ldots<i_r\leq N}\frac{1}{r}\left(1-\frac{p_{i_1}+p_{i_2}+\ldots+p_{i_r}}{r}\right)^{-1} &(26)\\ &=(N-\mu)\sum_{r=1}^{N}(-1)^{r+1}\\ &\qquad\sum_{1\leq i_1<\ldots<i_r\leq N}\frac{1}{r}\left(\sum_{j=0}^{\infty}\left(\frac{p_{i_1}+p_{i_2}+\ldots+p_{i_r}}{r}\right)^{j}\right) &(27)\end{aligned}$$

$$\leq (N-\mu)\sum_{r=1}^{N}(-1)^{r+1}\binom{N}{r}\frac{1}{r}\left(1+\frac{\mu}{N}\sum_{s=0}^{\infty}2^{-s}\right) \tag{28}$$

$$= (N-\mu)\ln N\left(1+\frac{2\mu}{N}\right) \tag{29}$$

$$< (N+\mu)\ln N \tag{30}$$

where (26) follows from substituting $\hat{p_i} = (1-p_i)/(N-\mu)$, (27) follows from the expansion of geometric sum with the fact that every p_i as well as the average $r^{-1}\sum_{j=1}^{r} p_{i_j}$ is between 0 and 1. Since we assume the universal set $\mathcal{N}$ is bounded above by $\frac{1}{2}$ using $p_i < \frac{1}{2}$ and expanding (27) we can get (28). Moreover (29) follows from lemma 2 and $\sum_{r=1}^{N} 1/r \leq \ln(N)$.

Substituting (30) into (21) and optimizing for g, we obtain $g^* = -1/\ln\left(\sum_{i=1}^{N}\hat{p}_i\,(1-p_i)\right)$. Such choice of g^* and the assumption $\mu \ll N$ allow (21) to be simplified as

$$T \geq e\mu\ln N \tag{31}$$

since the ratio between the expected stopping time and the expected non-defective items in a single negative test can be computed as

$$\begin{aligned}
&\frac{(N+\mu)\ln N}{g^*\left(\sum_{i=1}^{N}\hat{p}_i(1-p_i)\right)^{g^*}} \\
&\quad= (N+\mu)\ln N\left(-\ln\left(\sum_{i=1}^{N}\hat{p}_i(1-p_i)\right)\right) \\
&\quad= e\,(N+\mu)\ln N\left(-\ln\left(\frac{\sum_{i=1}^{N}(1-p_i)^2}{N-\mu}\right)\right) \\
&\quad= e\,(N+\mu)\ln N\left(-\ln\left(\frac{\sum_{i=1}^{N}(1-2p_i+{p_i}^2)}{N-\mu}\right)\right) \\
&\quad< e\,(N+\mu)\ln N\left(\ln\left(\frac{N-\mu}{N-2\mu}\right)\right) \\
&\quad\doteq e\mu\ln N.
\end{aligned}$$

Note that (21) only accounts for the expectation. Now we take variance in consideration. By Chernoff bound, the actual number of items in the negative tests can be smaller than $1-\alpha$ times the expected number with probability at most $\exp\left(-\alpha^2 T\right)$. In tail estimate of the coupon collector problem, with probability $N^{\frac{-\chi}{2}+1}$, a collector requires more than $\chi E[\mathcal{T}]$ coupons before he can collect a full set. Thus, using union bound over two error events, (21) and (31) shall be generalized as

$$(1-\alpha)\,T \geq e\chi\mu\ln N, \tag{32}$$

which does not hold with probability P_e at most $\exp\left(-\alpha^2 T\right) + N^{\frac{-\chi}{2}+1}$. Taking $\alpha = \frac{1}{2}$ in (32), we can bound

the error probability as

$$\begin{aligned} P_e \leq & \exp\left(-\alpha^2 T\right) + N^{\frac{-\chi}{2}+1} \\ \leq & \exp\left(-\frac{T}{4}\right) + N^{\frac{-\chi}{2}+1} \\ \leq & N^{-\frac{e\mu\chi}{2}} + N^{\frac{-\chi}{2}+1} \\ \leq & 2N^{\frac{-\chi}{2}+1}. \end{aligned}$$

If we take $2N^{\frac{-\chi}{2}+1}$ to be $N^{-\delta}$, we have $\chi \to 2(\delta+1)$ as $N \to \infty$. Hence, for large N, theorem 4 holds. ■

D. Proof of Theorem 5

Proof: For non-skewed universal set $\mathcal{N}$, we use the Pre-partitioned model with the following notations. Let $l \leq L$ be the total number of ample subsets such that an ample subset $\mathcal{U}_s$ is indexed by $s \in \{1, 2, \ldots, l\}$, μ_s be the sum of *a priori* probabilities of items in $\mathcal{U}_s$, n_s be the number of items in $\mathcal{U}_s$, $\mathbf{X}_s$ be the population vector for each $\mathcal{U}_s$, and $\bar{p}_s = N_s^{-1} \sum_{x_j \in \mathcal{U}_s}^{L} p_j$.

The total number of tests T is the sum of the total number of tests for ample subsets, denoted by T_1, and the total number of tests for unbounded non-ample subsets, denoted by T_2. By Theorem 4, with error probability at most $N_s^{-\delta}$ for each ample subset $\mathcal{U}_s$, T_1 can be computed as

$$\begin{aligned} T_1 \leq & 4e\left(1+\delta\right) \sum_{s=1}^{l} \mu_s \ln N_s \\ = & 4e\left(1+\delta\right) \sum_{s=1}^{l} \left(\sum_{i:X_i \in \mathcal{U}_s} p_i \ln \frac{1}{\bar{p}_s} + \mu_s \ln \mu_s \right) \\ \leq & 4e\left(1+\delta\right) \sum_{s=1}^{l} \left(2 \sum_{i:X_i \in \mathcal{U}_s} p_i \ln \frac{1}{p_i} + \mu_s \ln \mu_s \right) \qquad (33) \\ \leq & 12e\left(1+\delta\right) \sum_{s=1}^{l} H\left(\mathbf{X}_s\right) \qquad (34) \\ = & 12e\left(1+\delta\right) H\left(\mathbf{X}\right) \qquad (35) \end{aligned}$$

where inequality (33) follows from the fact that *well-balanced subsets* satisfy $p_i^2 \leq p_j \ \forall X_i, X_j \in \mathcal{U}_s$ and thus ${p_i}^2 \leq \bar{p}_s \ \forall X_i \in \mathcal{U}_s$, and inequality (34) follows directly.

As to unbounded non-ample subsets, the number of tests required is at most $L^2 + 2\mu$. Since $\mathcal{N}$ is non-skewed, we can bound L^2 as

$$\begin{aligned} L^2 < & \left\lceil \log_2\left(\log_2\left(2N/\bar{P}_e\right)\right)\right\rceil^2 \\ < & H\left(\mathbf{X}\right) \end{aligned}$$

and 2μ is at most $H(\mathbf{X})$ according to Definition 1. Thus, we have

$$T_2 < 2H(\mathbf{X}). \tag{36}$$

Putting (35) and (36) together, we can conclude the total number of tests is given by

$$\begin{aligned} T &= T_1 + T_2 \\ &< (12e+2)(1+\delta) H(\mathbf{X}) \end{aligned}$$

with error probability P_e satisfies $P_e \leq \sum_{s=1}^{l} N_s^{-\delta} + \bar{P}_e/2$.

Thus as a conclusion, we have $P_e \leq 2\Gamma^{-\delta+1} + \bar{P}_e/2$.

■